

FAST - (09703845.wspd)

File View Edit Tools Window Help

Drafts BRS: 8 and
Pending Active

L1: (9275) 324/769, 765, 767, 158.1.ccls.
L2: (37) ((determin\$4 or measur\$4) near5 capac
L3: (5) 1 and 2
L4: (2069) 257/48, 268, 335.ccls.
L5: (1) 2 and 4
L6: (5798) 365/174, 149.ccls.
L7: (0) 2 and 6

Failed
Saved

S1: (4) ("6069485" or ("5904490")).PN.
S2: (2) ("5610104").PN.
S3: (23044) transistor near2 structure
S4: (11021) transistor adj structure
S5: (6868) (transistor adj structure) and "257"
S6: (118) (base with gate with drain) with insu
S7: (13) ((transistor adj structure) and "257")
S8: (350) 324/769.ccls.
S9: (4) 324/769.ccls. and (determin\$4 near5 cap
S10: (4) ("5304925" | "5493231" | "5493238" | "
S11: (3) ("5194923" | "5268318" | "5600578").PN
S12: (371) (determin\$4 near5 capacitance) same
S13: (14) ((determin\$4 near5 capacitance) same

A BRS form IS&G form Image Text HTML

	U	I	Document ID	Issue Date	Pages	Title	Current OR	Current XR	Retrieval	Inventor	S	C	P	R	3	4
1	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 3889188	19750610	6	Time zero determination of FET reliability.	324/769			Trindade; David Charles	<input checked="" type="checkbox"/>					
2	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 4448400	19840515	22	Highly scalable dynamic RAM cell with self-sion	365/185.03	257/262; 257/300...2		Harari; Eliyahou	<input checked="" type="checkbox"/>					
3	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 4520466	19850528	14	Dynamic random access memory	365/210			Mashiko; Koichiro	<input checked="" type="checkbox"/>					
4	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 4589003	19860513	9	Solid state image sensor_comorising_photo	257/258	257/262; 257/293...2		Yamada; Hidetoshi et.al.	<input checked="" type="checkbox"/>					
5	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 5365477	19941115	12	Dynamic random access memory_device	365/174	257/110; 257/187...2		Cooper, Jr.; James A. et.al.	<input checked="" type="checkbox"/>					
6	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 5753946	19980519	18	Ferroelectric memory	257/295	257/E27.10; 257/E29		Naiki; Ihachi et al.	<input checked="" type="checkbox"/>					
7	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 5757204	19980526	16	Method and circuit for detecting_boron ("B") in	324/769	324/765		Nayak; Deepak Kumar et.al.	<input checked="" type="checkbox"/>					
8	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 5821766	19981013	15	Method and apparatus for measuring_the_metal	324/769	257/E21.53; 324/765		Kim; Sung-Ki et al.	<input checked="" type="checkbox"/>					
9	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 5835409	19981110	31	Compact page-erasable EEPROM	365/185.15	257/209; 257/206...2		Lambertson; Roy T. et.al.	<input checked="" type="checkbox"/>					

Hits Details HTML

Ready

NUM